

Notice of References Cited	Application/Control No. 10/594,144		Applicant(s)/Patent Under Reexamination OHNO ET AL.	
	Examiner RONAK PATEL		Art Unit 1794	Page 1 of 1

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NON-PATENT DOCUMENTS

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	V	Yamamoto et al., Surface Inteaction Forces of Well-Defined, High Density Polymer Brushes Studied by Atomic Force Microscopy. 1 . Effect of Chain Length, July, 06, 2000, American Chemical Society
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.